Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/576,246	SIRRINGHAUS ET AL.	
Examiner	Art Unit	_
Jae Lee	2823	

	SEARCHED		
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Search: TFT or (thin adj film adj transistor), ((semiconduct\$5 or active) adj (layer or region))	5/15/2007	JML
IEEE searches, google scholar searches	5/15/2007	JML